

**Search Notes**

Application/Control No.

10/801,872

Examiner

Benny Q. Tieu

Applicant(s)/Patent under  
Reexamination

MEEK ET AL.

Art Unit

2642

**SEARCHED**

Class	Subclass	Date	Examiner
379	211.01 211.02 201.01 196 127.01	7/22/2005	BQT
	142.05		
	93.03		
	142.05		
	114.25		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	7/22/2005	BQT